Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/607,668	MCELVAIN, JON S.	
Examiner	Art Unit	
Steven Kau	2625	

SEARCHED				
Class	Subclass	Date	Examiner	
358	3.27, 426.13	3/27/2007	SK	
SK	SK	3/27/2007	sĸ	
382	269, 233	3/27/2007	sĸ	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	3/23/2007	sĸ
Inventor Name search	3/23/2007	sĸ
Consulted with Wenping Chen, Primary Examiner, AU 2624	3/27/2007	sĸ
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